Exercise 1.10

Assume a 15 cm diameter wafer has a cost of 12, contains 84 dies, and has 0.020 defects/cm2. Assume a 20 cm diameter wafer has a cost of 15, contains 100 dies, and has 0.031 defects/cm2.

1.10.1 [10] <§1.5> Find the yield for both wafers.

1.10.2 [5] <§1.5> Find the cost per die for both wafers.

1.10.3 [5] <§1.5> If the number of dies per wafer is increased by 10% and the defects per area unit increases by 15%, fi nd the die area and yield.

1.10.4 [5] <§1.5> Assume a fabrication process improves the yield from 0.92 to 0.95. Find the defects per area unit for each version of the technology given a die area of 200 mm2.

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